## **IGBT - SMPS** 300 V

## FGH50N3

#### **Description**

Using ON Semiconductor's planar technology, this IGBT is ideal for many high voltage switching applications operating at high frequencies where low conduction losses are essential. This device has been optimized for medium frequency switch mode power supplies.

#### **Features**

- Low Saturation Voltage: V<sub>CE(sat)</sub> = 1.4 V Max
- Low  $E_{OFF} = 6.6 \text{ uJ/A}$
- SCWT =  $8 \mu s @ = 125 ^{\circ} C$
- 300 V Switching SOA Capability
- Positive Temperature Coefficient above 50 A
- This is a Pb-Free Device

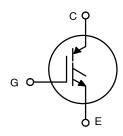
#### **Applications**

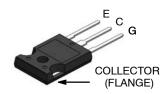
• SMPS



#### ON Semiconductor®

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TO-247-3LD CASE 340CK

#### **MARKING DIAGRAM**



\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Numeric Date Code &K = Lot Code

FGH50N3 = Specific Device Code

## **ORDERING INFORMATION**

See detailed ordering and shipping information on page 2 of this data sheet.

#### FGH50N3

## **MAXIMUM RATINGS** ( $T_C = 25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Ratings	Unit	
Collector to Emitter Breakdown Voltage	BV <sub>CES</sub>	300	V	
Collector Current Continuous	Tc = 25°C	I <sub>C</sub>	75	Α
	Tc = 110°C	1	75	Α
Collector Current Pulsed (Note 1)	I <sub>CM</sub>	240	Α	
Gate to Emitter Voltage Continuous	V <sub>GES</sub>	±20	V	
Gate to Emitter Voltage Pulsed	$V_{GEM}$	±30	V	
Switching Safe Operating Area at T <sub>J</sub> = 150°C, Figure 2	SSOA	150 A at 300 V		
Single Pulse Avalanche Energy, $I_{CE}$ = 30 A, L = 1.78 mH, $V_{DD}$	E <sub>AS</sub>	800	mJ	
Single Pulse Reverse Avalanche Energy, I <sub>EC</sub> = 30 A, L = 1.78	mH, V <sub>DD</sub> = 50 V	E <sub>ARV</sub>	800	mJ
Power Dissipation Total Tc = 25°C		P <sub>D</sub>	463	W
Power Dissipation Derating Tc > 25°C		1	3.7	W/°C
Operating Junction Temperature Range	T <sub>J</sub>	-55 to +150	°C	
Storage Temperature Range Range	T <sub>STG</sub>	-55 to +150	°C	
Short Circuit Withstand Time (Note 2)	t <sub>SC</sub>	8	μs	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Pulse width limited by maximum junction temperature.

2. V<sub>CE(PK)</sub> = 180 V, T<sub>J</sub> = 125°C, V<sub>GE</sub> = 12 Vdc, R<sub>G</sub> = 5 Ω

## PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Tape Width	Quantity
FGH50N3	FGH50N3	TO-247	N/A	30

## THERMAL CHARACTERISTICS

Ī	Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
ſ	Thermal Resistance, Junction-Case	$R_{ heta JC}$	TO-247	_	_	0.27	°C/W

## **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Test Conditions		Min	Тур	Max	Unit
OFF STATE CHARACTERISTICS		-					
Collector to Emitter Breakdown Voltage	BV <sub>CES</sub>	$I_{CE} = 250 \mu A, V_{GE} = 0 V,$		300	-	-	V
Emitter to Collector Breakdown Voltage	BV <sub>ECS</sub>	I <sub>EC</sub> = 10 mA, V <sub>GE</sub> = 0 V		15	-	-	V
Collector to Emitter Leakage Current	I <sub>CES</sub>	V <sub>CE</sub> = 300 V	V <sub>CE</sub> = 300 V T <sub>J</sub> = 25°C		_	250	μΑ
			T <sub>J</sub> = 125°C	_	_	2.0	mA
Gate to Emitter Leakage Current	I <sub>GES</sub>	V <sub>GE</sub> = ±20 V	•	_	_	±250	nA
ON STATE CHARACTERISTICs							
Collector to Emitter Saturation Voltage	V <sub>CE(SAT)</sub>	I <sub>CE</sub> = 30 A, V <sub>GE</sub> = 15 V T <sub>J</sub> = 25°C		-	1.30	1.4	V
			T <sub>J</sub> = 125°C	-	1.25	1.4	V
DYNAMIC CHARACTERISTICS							
Gate Charge	Q <sub>G(ON)</sub>	I <sub>CE</sub> = 30 A, V <sub>CE</sub> = 150 V	V <sub>GE</sub> = 15 V	-	180	-	nC
			V <sub>GE</sub> = 20 V	-	228	-	nC
Gate to Emitter Threshold Voltage	V <sub>GE(TH)</sub>	$I_{CE}$ = 250 $\mu$ A, $V_{CE}$ = $V_{GE}$	-	4.0	4.8	5.5	V
Gate to Emitter Plateau Voltage	$V_{GEP}$	I <sub>CE</sub> = 30 A, V <sub>CE</sub> = 150 V		-	7.0	-	V

#### FGH50N3

#### **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = 25°C unless otherwise noted) (continued)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit	
SWITCHING CHARACTERISTICS							
Switching SOA	SSOA	$T_J = 150^{\circ} C, R_G = 5 \Omega, V_{GE} = 15 V, L = 25 \mu H, V_{CE} = 300 V$	150	-	_	Α	
Current Turn-On Delay Time	t <sub>d(ON)I</sub>	IGBT and Diode at T <sub>J</sub> = 25°C,	-	20	-	ns	
Current Rise Time	t <sub>rl</sub>	I <sub>CE</sub> = 30 A, V <sub>CE</sub> = 180 V,	-	15	-	ns	
Current Turn-Off Delay Time	t <sub>d(OFF)</sub> I	$V_{GE}$ = 15 V, $R_{G}$ = 5 Ω, , L = 100 μH, Test Circuit – Figure 20	-	135	-	ns	
Current Fall Time	t <sub>fl</sub>		-	12	-	ns	
Turn-On Energy (Note 3)	E <sub>ON2</sub>		-	130	-	μJ	
Turn-Off Energy Loss (Note 4)	E <sub>OFF</sub>		-	92	120	μJ	
Current Turn-On Delay Time	t <sub>d(ON)I</sub>	IGBT and Diode at T <sub>J</sub> = 125°C,	-	19	-	ns	
Current Rise Time	t <sub>rl</sub>	I <sub>CE</sub> = 30 A, V <sub>CE</sub> = 180 V,	-	13	-	ns	
Current Turn-Off Delay Time	t <sub>d(OFF)</sub> I	$\begin{array}{l} V_{GE} = 15 \text{ V,} \\ R_G = 5  \Omega,  , \\ L = 100  \mu\text{H,} \\ \text{Test Circuit} - \text{Figure 20} \end{array}$	-	155	190	ns	
Current Fall Time	t <sub>fl</sub>		_	7	15	ns	
Turn-On Energy (Note 3)	E <sub>ON2</sub>		-	225	270	μJ	
Turn-Off Energy (Note 4)	E <sub>OFF</sub>		_	135	200	μJ	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

<sup>3.</sup> E<sub>ON2</sub> is the turn-on loss when a typical diode is used in the test circuit and the diode is at the same T<sub>J</sub> as the IGBT. The diode type is specified in Figure 20.

Turn-Off Energy Loss (E<sub>OFF</sub>) is defined as the integral of the instantaneous power loss starting at the trailing edge of the input pulse and ending at the point where the collector current equals zero (I<sub>CE</sub> = 0 A). All devices were tested per JEDEC Standard No. 24–1 Method for Measurement of Power Device Turn-Off Switching Loss. This test method produces the true total Turn-Off Energy Loss.

#### TYPICAL PERFORMANCE CURVES (T, = 25°C unless otherwise noted)

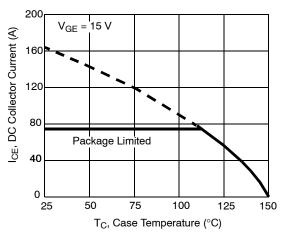


Figure 1. DC Collector Current vs. Case Temperature

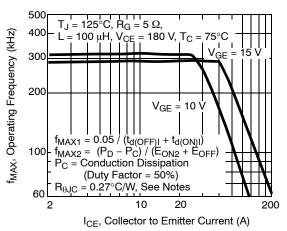


Figure 3. Operating Frequency vs. Collector to Emitter Current

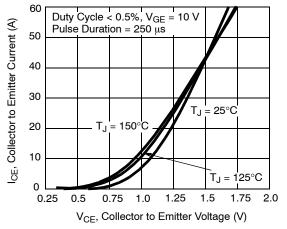


Figure 5. Collector to Emitter On-State Voltage

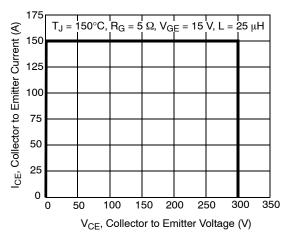
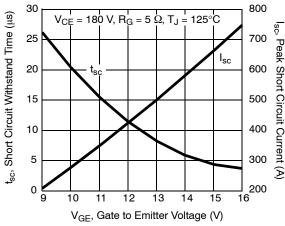


Figure 2. Minimum Switching Safe Operating Area



**Figure 4. Short Circuit Withstand Time** 

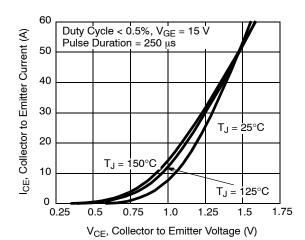


Figure 6. Collector to Emitter On-State Voltage

## TYPICAL PERFORMANCE CURVES (T<sub>J</sub> = 25°C unless otherwise noted) (continued)

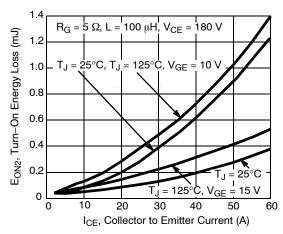


Figure 7. Turn-On Energy Loss vs. Collector to Emitter Current

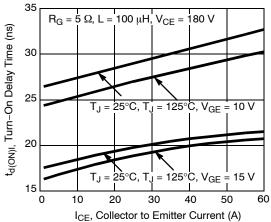


Figure 9. Turn-On Delay Time vs. Collector to Emitter Current

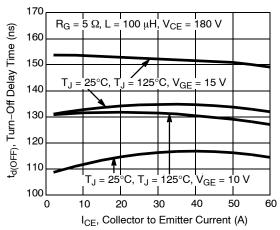


Figure 11. Turn-Off Delay Time vs. Collector to Emitter Current

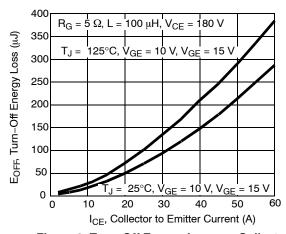


Figure 8. Turn-Off Energy Loss vs. Collector to Emitter Current

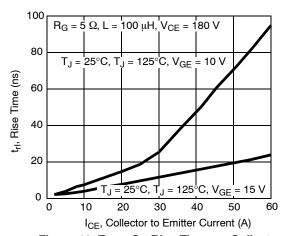


Figure 10. Turn-On Rise Time vs. Collector to Emitter Current

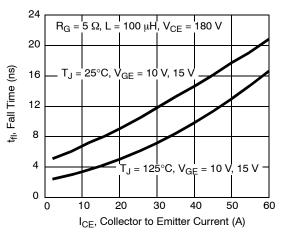


Figure 12. Fall Time vs. Collector to Emitter

#### TYPICAL PERFORMANCE CURVES (T<sub>J</sub> = 25°C unless otherwise noted) (continued)

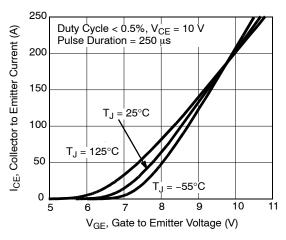


Figure 13. Transfer Characteristics

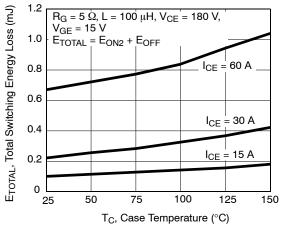


Figure 15. Total Switching Loss vs. Case Temperature

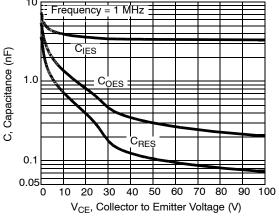


Figure 17. Capacitance vs. Collector to Emitter Voltage

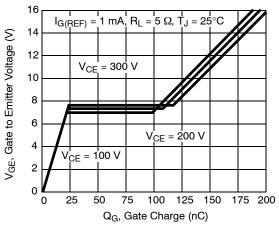


Figure 14. Gate Charge

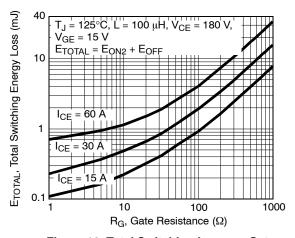


Figure 16. Total Switching Loss vs. Gate Resistance

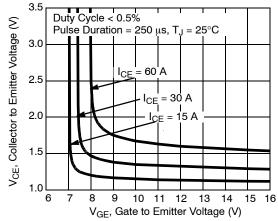


Figure 18. Collector to Emitter On-State Voltage vs. Gate to Emitter Voltage

## $\textbf{TYPICAL PERFORMANCE CURVES} \ (T_J = 25^{\circ}\text{C unless otherwise noted}) \ (\text{continued})$

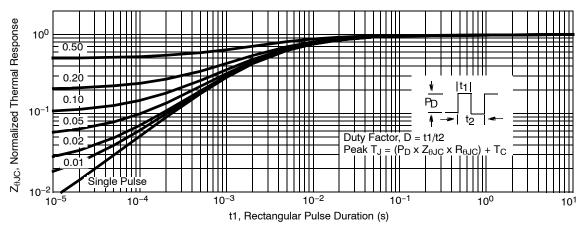


Figure 19. IGBT Normalized Transient Thermal Impedance,
Junction to Case

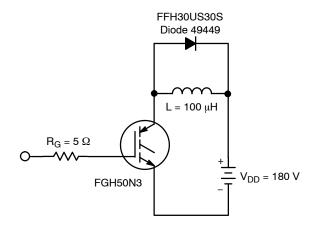


Figure 20. Inductive Switching Test Circuit

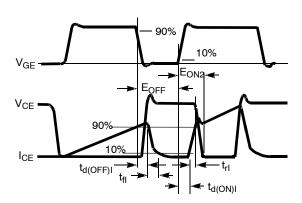
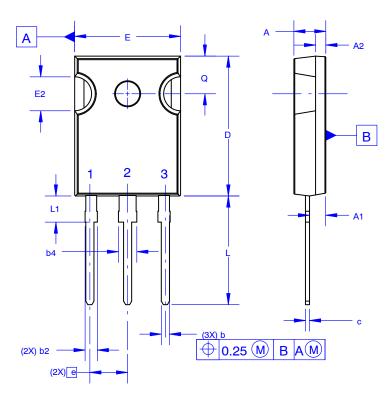


Figure 21. Switching Test Waveforms

#### TO-247-3LD SHORT LEAD

CASE 340CK ISSUE A





- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 2009.
- D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

# GENERIC MARKING DIAGRAM\*



XXXX = Specific Device Code

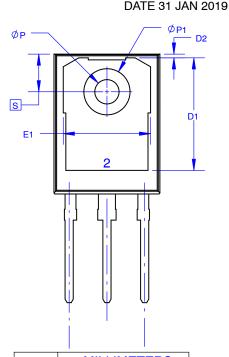
A = Assembly Location

Y = Year

WW = Work Week

ZZ = Assembly Lot Code

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.



DIM	MILLIMETERS				
DIIVI	MIN	NOM	MAX		
Α	4.58	4.70	4.82		
A1	2.20	2.40	2.60		
A2	1.40	1.50	1.60		
b	1.17	1.26	1.35		
b2	1.53	1.65	1.77		
b4	2.42	2.54	2.66		
С	0.51	0.61	0.71		
D	20.32	20.57	20.82		
D1	13.08	~	~		
D2	0.51	0.93	1.35		
E	15.37	15.62	15.87		
E1	12.81	~	~		
E2	4.96	5.08	5.20		
е	~	5.56	~		
L	15.75	16.00	16.25		
L1	3.69	3.81	3.93		
ØΡ	3.51	3.58	3.65		
Ø <b>P1</b>	6.60	6.80	7.00		
Q	5.34	5.46	5.58		
S	5.34	5.46	5.58		

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DESCRIPTION:	TO-247-3LD SHORT LEAD		PAGE 1 OF 1	

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